



1M WORD × 16 BIT LOW POWER PSEUDO SRAM

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1. GENERAL DESCRIPTION

W964B6BBN is a 16M bits CMOS pseudo static random access memory (Pseudo SRAM), organized as 1M words x 16 bits. Using advanced single transistor DRAM architecture and 0.175 μm process technology; W964B6BBN delivers fast access cycle time and low power consumption. It is suitable for mobile device application such as Cellular Phone and PDA, which high-density buffer is needed and power dissipation is most concerned

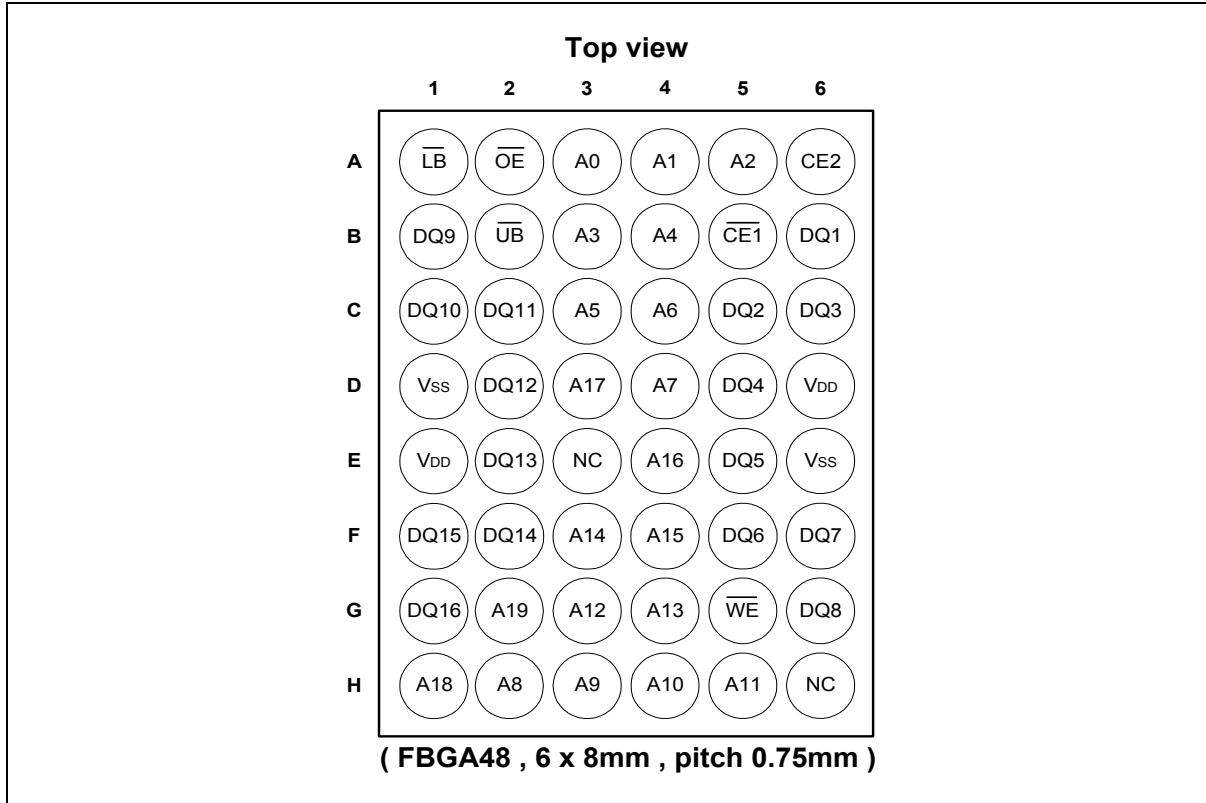
2. FEATURES

- Asynchronous SRAM interface
- Fast access cycle time:
 - $t_{RC} = 70 \text{ nS} (-70), 80 \text{ nS} (-80)$
- Low power consumption:
 - $I_{DDA1} = 20 \text{ mA Max.}$
 - $I_{DDS1} = 70 \mu\text{A Max.}$
- Byte write control
- Wide operating conditions:
 - $V_{DD} = +2.3\text{V to } +2.7\text{V}$
- Temperature
 - $T_A = 0^\circ\text{C to } +70^\circ\text{C}$
 - $T_A = -25^\circ\text{C to } +85^\circ\text{C (Extended temperature)}$
 - $T_A = -40^\circ\text{C to } +85^\circ\text{C (Industrial temperature)}$

3. PRODUCT OPTIONS

| PARAMETER | W964B6BBN70 | W964B6BBN80 |
|------------|-----------------------|-----------------------|
| t_{RC} | 70 nS Min. | 80 nS Min. |
| I_{DDS1} | 70 $\mu\text{A Max.}$ | 70 $\mu\text{A Max.}$ |
| I_{DDA1} | 20 mA | 20 mA |
| V_{DD} | 2.3V to 2.7V | 2.3V to 2.7V |

4. BALL CONFIGURATION

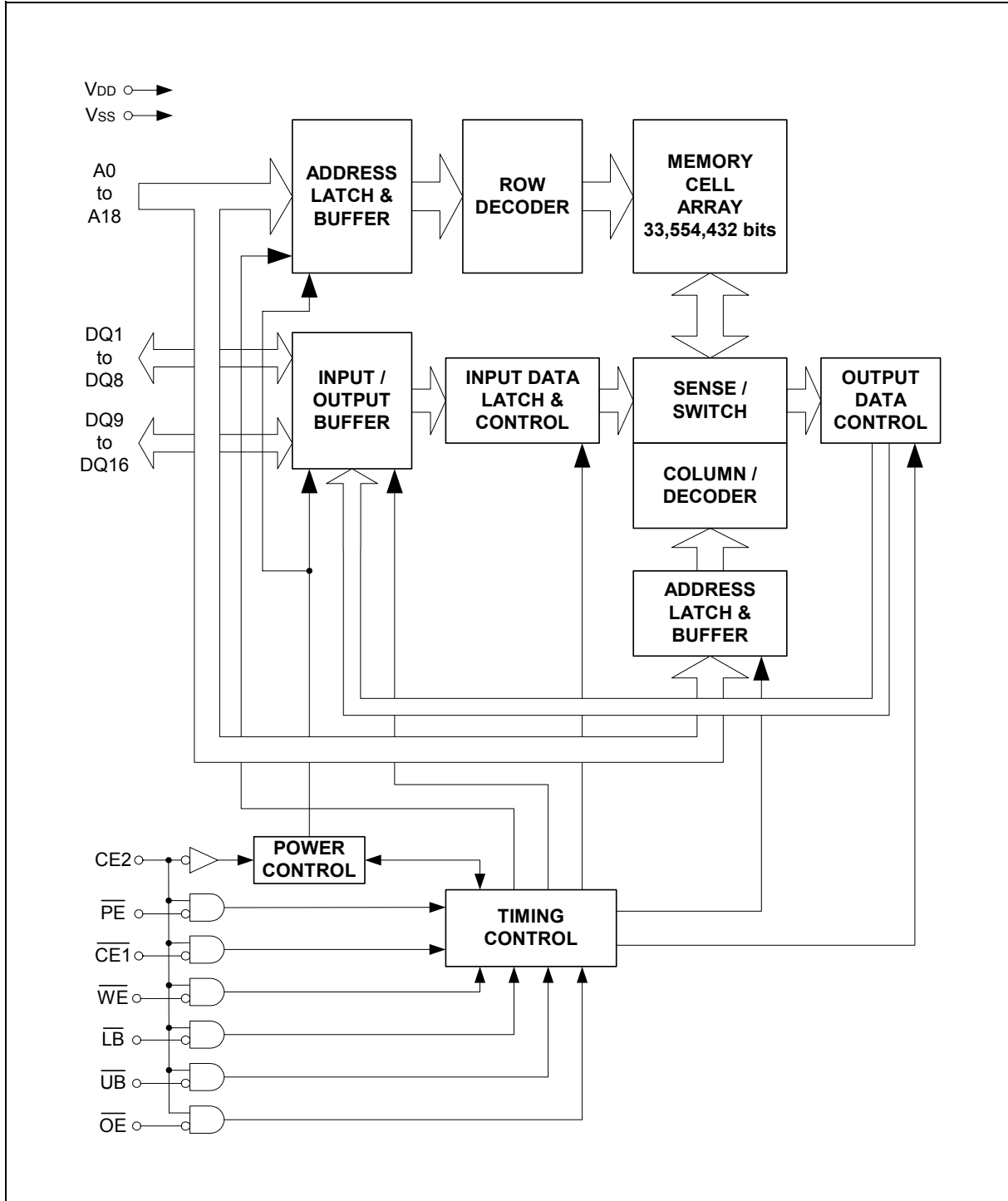


5. BALL DESCRIPTION

| SYMBOL | DESCRIPTION |
|--------------|---|
| A0 – A19 | Address input |
| CE1 | Chip Enable Input 1, Low: Enable |
| CE2 | Chip Enable Input 2, High: Enable, Low: Enter Power Down mode |
| WE | Write enable input |
| OE | Output Enable input |
| LB | Lower byte write control |
| UB | Upper byte write control |
| I/O0 – I/O15 | Data inputs/outputs |
| VDD | Power supply |
| Vss | Ground |
| NC | No Connection |



6. BLOCK DIAGRAM





7. FUNCTION TRUTH TABLE

| Mode | Note | CE2 | $\overline{\text{CE1}}$ | $\overline{\text{WE}}$ | $\overline{\text{OE}}$ | $\overline{\text{LB}}$ | $\overline{\text{UB}}$ | A0-18 | DQ1-8 | DQ9-16 | I _{DD} | Data Retention |
|--------------------|------|-----|-------------------------|------------------------|------------------------|------------------------|------------------------|--------------|--------|--------|------------------|----------------|
| Standby (Deselect) | | H | H | X | X | X | X | X | High-Z | High-Z | I _{DDs} | Yes |
| Output Disable | *1 | | L | H | H | X | X | *5 | High-Z | High-Z | I _{DDA} | Yes |
| No Read | | | | H | L | H | H | Valid | High-Z | High-Z | | |
| Read | *2 | | | L | *4 | Valid | Output Valid | Output Valid | | | | |
| Write (Upper Byte) | | | | H | L | Valid | Invalid | Input Valid | | | | |
| Write (Lower Byte) | | | | L | H | Valid | Input Valid | Invalid | | | | |
| Write (Word) | | | | L | L | Valid | Input Valid | Input Valid | | | | |
| Power Down | *3 | | L | X | X | X | X | X | High-Z | High-Z | I _{DDP} | No/Yes |

Notes: L = V_{IL}, H = V_{IH}, X can be either V_{IL} or V_{IH}, High-Z = High impedance, KEY = Key Address.

*1: Output Disable mode should not be kept longer than 1 μS.

*2: Byte control at Read mode is not supported.

*3: Power Down mode can be entered from Standby state and all DQ pins are in High-Z state. I_{DDP} current and data retention depend on the selection of Power Down Program.

*4: Either or both $\overline{\text{LB}}$ and $\overline{\text{UB}}$ must be Low for Read operation.

*5: Can be either V_{IL} or V_{IH} but must be valid before Read or Write.



8. ELECTRICAL CHARACTERISTICS

Absolute Maximum Ratings

| PARAMETER | SYMBOL | VALUE | UNIT |
|---|------------------------------------|--------------|------|
| Voltage of V _{DD} Supply Relative to V _{SS} | V _{DD} | -0.5 to +3.6 | V |
| Voltage at Any Pin Relative to V _{SS} | V _{IN} , V _{OUT} | -0.5 to +3.6 | V |
| Short Circuit Output Current | I _{OUT} | ±50 | mA |
| Storage Temperature | T _{STG} | -55 to +125 | °C |

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

Recommended Operation Conditions

(Reference to V_{SS})

| PARAMETER | NOTES | SYMBOL | MIN. | MAX. | UNIT |
|--------------------------|-------|-----------------|------|----------------------|------|
| Supply Voltage | | V _{DD} | 2.3 | 2.7 | V |
| | | V _{SS} | 0 | 0 | V |
| High Level Input Voltage | *1 | V _{IH} | 2.0 | V _{DD} +0.3 | V |
| Low Level Input Voltage | *2 | V _{IL} | -0.3 | 0.4 | V |
| Ambient Temperature | | T _A | 0 | 70 | °C |
| Ambient Temperature | | T _A | -25 | 85 | °C |
| Ambient Temperature | | T _A | -40 | 85 | °C |

Notes:

*1: Maximum DC voltage on input and I/O pins are V_{DD} +0.3V. During voltage transitions, inputs may positive overshoot to V_{DD} +1.0V for periods of up to 5 nS.

*2: Minimum DC voltage on input and I/O pins are -0.3V. During voltage transitions, inputs may negative overshoot to -1.0V for periods of up to 5 nS.

WARNING: Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the datasheet. Users considering application outside the listed conditions are advised to contact their Winbond representative beforehand.



Capacitance

Test conditions: $T_A = 25^\circ\text{C}$, $f = 1.0\text{ MHz}$

| SYMBOL | DESCRIPTION | TEST SETUP | TYP. | MAX. | UNIT |
|--------|-------------------------------|---------------|------|------|------|
| CIN1 | Address Input Capacitance | $V_{IN} = 0V$ | - | 5 | pF |
| CIN2 | Control Input Capacitance | $V_{IN} = 0V$ | - | 5 | pF |
| CIO | Data Input/Output Capacitance | $V_{IO} = 0V$ | - | 8 | pF |

DC Characteristics

(Under Recommended Operating Conditions unless otherwise noted) notes*1, *2, *3

| PARAMETER | SYM. | TEST CONDITIONS | MIN. | MAX. | UNIT | |
|---------------------------|--------|--|---|------|---------------|----|
| Input Leakage Current | ILI | $V_{IN} = V_{SS}$ to V_{DD} | -1.0 | +1.0 | μA | |
| Output Leakage Current | ILO | $V_{OUT} = V_{SS}$ to V_{DD} , Output Disable | -1.0 | +1.0 | μA | |
| Output High Voltage Level | VOH | $V_{DD} = V_{DD}$, $I_{OH} = -0.5\text{ mA}$ | 1.8 | - | V | |
| Output Low Voltage Level | VOL | $I_{OL} = 1\text{ mA}$ | - | 0.4 | V | |
| Standby Current | (TTL) | I_{DD5} $V_{DD} = V_{DD}\text{ Max.},$ $V_{IN} = V_{IH}$ or V_{IL} $\overline{CE1} = \overline{CE2} = V_{IH}$ | - | 3 | mA | |
| | (CMOS) | I_{DD51} $V_{DD} = V_{DD}\text{ Max.},$ $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{DD} - 0.2V,$ $\overline{CE1} = \overline{CE2} \geq V_{DD} - 0.2V$ | - | 70 | μA | |
| Active Current | IDDA1 | $V_{DD} = V_{DD}\text{ Max.},$ $V_{IN} = V_{IH}$ or $V_{IL},$ $\overline{CE1} = V_{IL}$ and $\overline{CE2} = V_{IH},$ $I_{OUT} = 0\text{ mA}$ | $t_{RC} / t_{WC} =$ Minimum | - | 20 | mA |
| | IDDA2 | | $t_{RC} / t_{WC} =$ $1\ \mu\text{S}$ | - | 3 | mA |

Notes:

- *1: All voltages are reference to V_{SS} .
- *2: DC Characteristics are measured after following POWER-UP timing.
- *3: I_{OUT} depends on the output load conditions.



AC Characteristics

(Under Recommended Operating Conditions unless otherwise noted)

Read Operation

| PARAMETER | SYM. | -70 | | -80 | | UNIT | NOTES |
|---|-----------------------|------|------|------|------|------|----------------|
| | | Min. | Max. | Min. | Max. | | |
| Read Cycle Time | t _{RC} | 70 | - | 80 | - | nS | |
| Chip Enable Access Time | t _{CE} | - | 65 | - | 75 | nS | *1, *3 |
| Output Enable Access Time | t _{OE} | - | 40 | - | 45 | nS | *1 |
| Address Access Time | t _{AA} | - | 65 | - | 75 | nS | *1 |
| Output Data Hold Time | t _{OH} | 5 | - | 5 | - | nS | *1 |
| $\overline{\text{CE1}}$ Low to Output Low-Z | t _{CLZ} | 5 | - | 5 | - | nS | *2 |
| $\overline{\text{OE}}$ Low to Output Low-Z | t _{OLZ} | 0 | - | 0 | - | nS | *2 |
| $\overline{\text{CE1}}$ High to Output High-Z | t _{CHZ} | - | 20 | - | 25 | nS | *2 |
| $\overline{\text{OE}}$ High to Output High-Z | t _{OHZ} | - | 20 | - | 25 | nS | *2 |
| Address Setup Time to $\overline{\text{CE1}}$ Low | t _{ASC} | -5 | - | -5 | - | nS | *4 |
| Address Setup Time to $\overline{\text{OE}}$ Low | t _{ASO} | 30 | - | 35 | - | nS | *3, *5 |
| | t _{ASO[ABS]} | 10 | - | 10 | - | nS | *6 |
| $\overline{\text{LB}} / \overline{\text{UB}}$ Setup Time to $\overline{\text{CE1}}$ Low | t _{BSC} | -5 | - | -5 | - | nS | |
| $\overline{\text{LB}} / \overline{\text{UB}}$ Setup Time to $\overline{\text{OE}}$ Low | t _{BSO} | 10 | - | 10 | - | nS | |
| Address Invalid Time | t _{AX} | - | 5 | - | 5 | nS | |
| Address Hold Time from $\overline{\text{CE1}}$ Low | t _{CLAH} | 70 | - | 80 | - | nS | |
| Address Hold Time from $\overline{\text{OE}}$ Low | t _{OLAH} | 40 | - | 45 | - | nS | *9 |
| Address Hold Time from $\overline{\text{CE1}}$ High | t _{CHAH} | -5 | - | -5 | - | nS | |
| Address Hold Time from $\overline{\text{OE}}$ High | t _{OHAH} | -5 | - | -5 | - | nS | |
| $\overline{\text{LB}} / \overline{\text{UB}}$ Hold Time from $\overline{\text{CE1}}$ High | t _{CHBH} | -5 | - | -5 | - | nS | |
| $\overline{\text{LB}} / \overline{\text{UB}}$ Hold Time from $\overline{\text{OE}}$ High | t _{OHBH} | -5 | - | -5 | - | nS | |
| $\overline{\text{CE1}}$ Low to $\overline{\text{OE}}$ Low Delay Time | t _{CLOL} | 25 | 1000 | 30 | 1000 | nS | *3, *5, *7, *8 |
| $\overline{\text{OE}}$ Low to $\overline{\text{CE1}}$ High Delay Time | t _{OLCH} | 35 | - | 40 | - | nS | *7 |
| $\overline{\text{CE1}}$ High Pulse Width | t _{CP} | 12 | - | 15 | - | nS | |
| $\overline{\text{OE}}$ High Pulse Width | t _{OP} | 25 | 1000 | 30 | 1000 | nS | *5, *7, *8 |
| | t _{OP[ABS]} | 12 | - | 15 | - | ns | *6 |



Read Operation, Continued

Notes:

- *1: The output load is 30 pF.
- *2: The output load is 5 pF.
- *3: The t_{CE} is applicable if \overline{OE} is brought to Low before $\overline{CE1}$ goes Low and is also applicable if actual value of both or either t_{ASO} or t_{CLOL} is shorter than specified value.
- *4: Applicable if \overline{OE} is brought to Low before $\overline{CE1}$ goes Low.
- *5: The t_{ASO} , $t_{CLOL}(\text{min.})$ and $t_{OP}(\text{min.})$ are reference values when the access time is determined by t_{OE} . If actual value of each parameter is shorter than specified minimum value, t_{OE} become longer by the amount of subtracting actual value from specified minimum value.

For example, if actual t_{ASO} , $t_{ASO}(\text{actual})$, is shorter than specified minimum value, $t_{ASO}(\text{min.})$, during \overline{OE} control access (i.e., $\overline{CE1}$ stays Low), the t_{OE} become $t_{OE}(\text{max.}) + t_{ASO}(\text{min.}) - t_{ASO}(\text{actual})$.
- *6: The $t_{ASO}[\text{ABS}]$ and $t_{OP}[\text{ABS}]$ is the absolute minimum value during \overline{OE} control access.
- *7: If actual value of either t_{CLOL} or t_{OP} is shorter than specified minimum value, both t_{OLAH} and t_{OLCH} become $t_{RC}(\text{min.}) - t_{CLOL}(\text{actual})$ or $t_{RC}(\text{min.}) - t_{OP}(\text{actual})$.
- *8: Maximum value is applicable if $\overline{CE1}$ is kept at low.



AC Characteristics, Continued

Write Operation

| PARAMETER | SYM. | -70 | | -80 | | UNIT | NOTES |
|---|----------------|------|------|------|------|------|------------|
| | | Min. | Max. | Min. | Max. | | |
| Write Cycle Time | t_{WC} | 70 | - | 80 | - | nS | *1 |
| Address Setup Time | t_{AS} | 0 | - | 0 | - | nS | *2 |
| Address Hold Time | t_{AH} | 35 | - | 40 | - | nS | *2 |
| $\overline{CE1}$ Write Setup Time | t_{CS} | 0 | 1000 | 0 | 1000 | nS | |
| $\overline{CE1}$ Write Hold Time | t_{CH} | 0 | 1000 | 0 | 1000 | nS | |
| \overline{WE} Setup Time | t_{WS} | 0 | - | 0 | - | nS | |
| \overline{WE} Hold Time | t_{WH} | 0 | - | 0 | - | nS | |
| \overline{LB} and \overline{UB} Setup Time | t_{BS} | -5 | - | -5 | - | nS | |
| \overline{LB} and \overline{UB} Hold Time | t_{BH} | -5 | - | -5 | - | nS | |
| \overline{OE} Setup Time | t_{OES} | 0 | 1000 | 0 | 1000 | nS | *3 |
| \overline{OE} Hold Time | t_{OEH} | 30 | 1000 | 35 | 1000 | nS | *3, *4 |
| | $t_{OEH[ABS]}$ | 12 | - | 15 | - | nS | *5 |
| \overline{OE} High to $\overline{CE1}$ Low Setup Time | t_{OHCL} | -5 | - | -5 | - | nS | *6 |
| \overline{OE} High to Address Hold Time | t_{OHAH} | -5 | - | -5 | - | nS | *7 |
| $\overline{CE1}$ Write Pulse Width | t_{CW} | 45 | - | 50 | - | nS | *1, *8 |
| \overline{WE} Write Pulse Width | T_{WP} | 45 | - | 50 | - | nS | *1, *8 |
| $\overline{CE1}$ Write Recovery Time | t_{WRC} | 10 | - | 15 | - | nS | *1, *9 |
| \overline{WE} Write Recovery Time | t_{WR} | 10 | 1000 | 15 | 1000 | nS | *1, *3, *9 |
| Data Setup Time | t_{DS} | 15 | - | 20 | - | nS | |
| Data Hold Time | t_{DH} | 0 | - | 0 | - | nS | |
| $\overline{CE1}$ High Pulse Width | t_{CP} | 12 | - | 15 | - | nS | *9 |



Write Operation, Continued

Notes:

- *1: Minimum value must be equal or greater than the sum of actual t_{CW} (or t_{WP}) and t_{WRC} (or t_{WR}).
- *2: New write address is valid from either $\overline{CE1}$ or \overline{WE} is brought to High.
- *3: The t_{OE} is specified from end of $t_{WC}(\min.)$. The $t_{OE}(\min.)$ is a reference value when the access time is determined by t_{OE} .
If actual value, $t_{OE}(\text{actual})$ is shorter than specified minimum value, t_{OE} become longer by the amount of subtracting actual value from specified minimum value.
- *4: The $t_{OE}(\max.)$ is applicable if $\overline{CE1}$ is kept at Low and both \overline{WE} and \overline{OE} are kept at High.
- *5: The $t_{OE}[\text{ABS}]$ is the absolute minimum value if write cycle is terminated by \overline{WE} and $\overline{CE1}$ stays Low.
- *6: $t_{OHCL}(\min.)$ must be satisfied if read operation is not performed prior to write operation.
In case \overline{OE} is disabled after $t_{OHCL}(\min.)$, \overline{WE} Low must be asserted after $t_{RC}(\min.)$ from $\overline{CE1}$ Low. In other words, read operation is initiated if $t_{OHCL}(\min.)$ is not satisfied.
- *7: Applicable if $\overline{CE1}$ stays Low after read operation.
- *8: t_{CW} and t_{WP} is applicable if write operation is initiated by $\overline{CE1}$ and \overline{WE} , respectively.
- *9: t_{WRC} and t_{WR} is applicable if write operation is terminated by $\overline{CE1}$ and \overline{WE} , respectively.
The $t_{WR}(\min.)$ can be ignored if $\overline{CE1}$ is brought to High together or after \overline{WE} is brought to High. In such case, the $t_{CP}(\min.)$ must be satisfied.



AC Characteristics, Continued

Power Down and Power Down Program Parameters

| PARAMETER | SYM. | -70 | | -80 | | UNIT | NOTES |
|--|-------------------|------|------|------|------|------|-------|
| | | Min. | Max. | Min. | Max. | | |
| CE2 Low Setup Time for Power Down Entry | t _{CSP} | 10 | - | 10 | - | nS | |
| CE2 Low Hold Time after Power Down Entry | t _{C2LP} | 70 | - | 80 | - | nS | |
| CE1 High Setup Time following CE2 High after Power Down Exit | t _{CHS} | 10 | - | 10 | - | nS | |

Other Timing Parameters

| PARAMETER | SYM. | -70 | | -80 | | UNIT | NOTES |
|--|-------------------|------|------|------|------|------|-------|
| | | Min. | Max. | Min. | Max. | | |
| CE1 High to OE Invalid Time for Standby Entry | t _{CHOX} | 10 | - | 10 | - | nS | |
| CE1 High to WE Invalid Time for Standby Entry | t _{CHWX} | 10 | - | 10 | - | nS | *1 |
| CE2 Low Hold Time after Power-up | t _{C2LH} | 50 | - | 50 | - | μS | *2 |
| CE2 High Hold Time after Power-up | t _{C2HL} | 50 | - | 50 | - | μS | *3 |
| CE1 High Hold Time following CE2 High after Power-up | t _{CHH} | 350 | - | 350 | - | μS | *2 |
| Input Transition Time | t _T | 1 | 25 | 1 | 25 | nS | *4 |

Notes:

- *1: Some data might be written into any address location if t_{CHWX}(min.) is not satisfied.
- *2: Must satisfy t_{CHH}(min.) after t_{C2LH}(min.).
- *3: Requires Power Down mode entry and exit after t_{C2HL}.
- *4: The Input Transition Time (t_T) at AC testing is 5ns as shown in below. If actual t_T is longer than 5 nS, it may violate AC specified of some timing parameters.

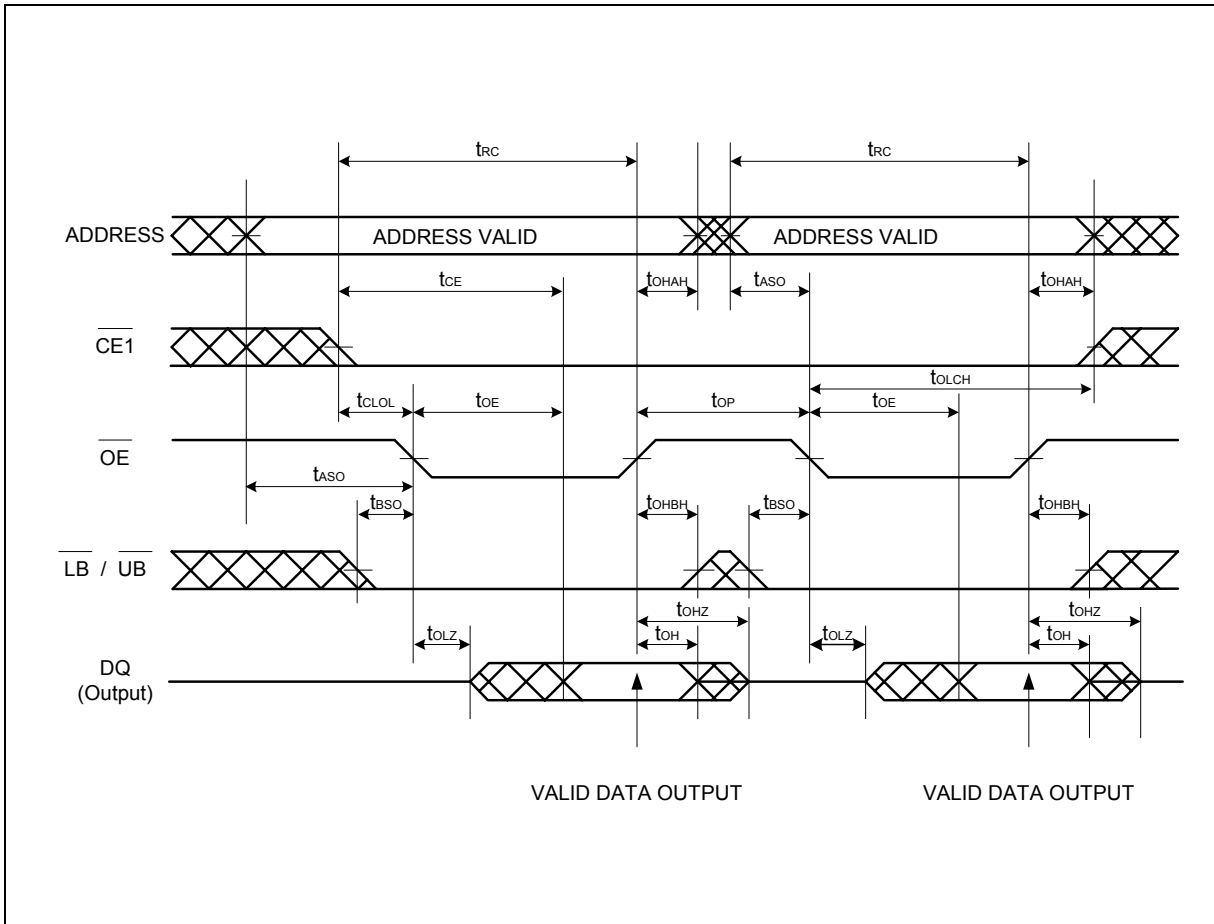
AC Test Conditions

| SYMBOL | DESCRIPTION | TEST SETUP | VALUE | UNIT | NOTE |
|------------------|--------------------------------|---|-------|------|------|
| V _{IH} | Input High Level | V _{DD} = 2.3V to 2.7V | 2.0 | V | |
| V _{IL} | Input Low Level | V _{DD} = 2.3V to 2.7V | 0.4 | V | |
| V _{REF} | Input Timing Measurement Level | V _{DD} = 2.3V to 2.7V | 1.1 | V | |
| T _T | Input Transition Time | Between V _{IL} and V _{IH} | 5 | nS | |



9. TIMING WAVEFORMS

Read Timing #1 ($\overline{\text{OE}}$ Control Access)



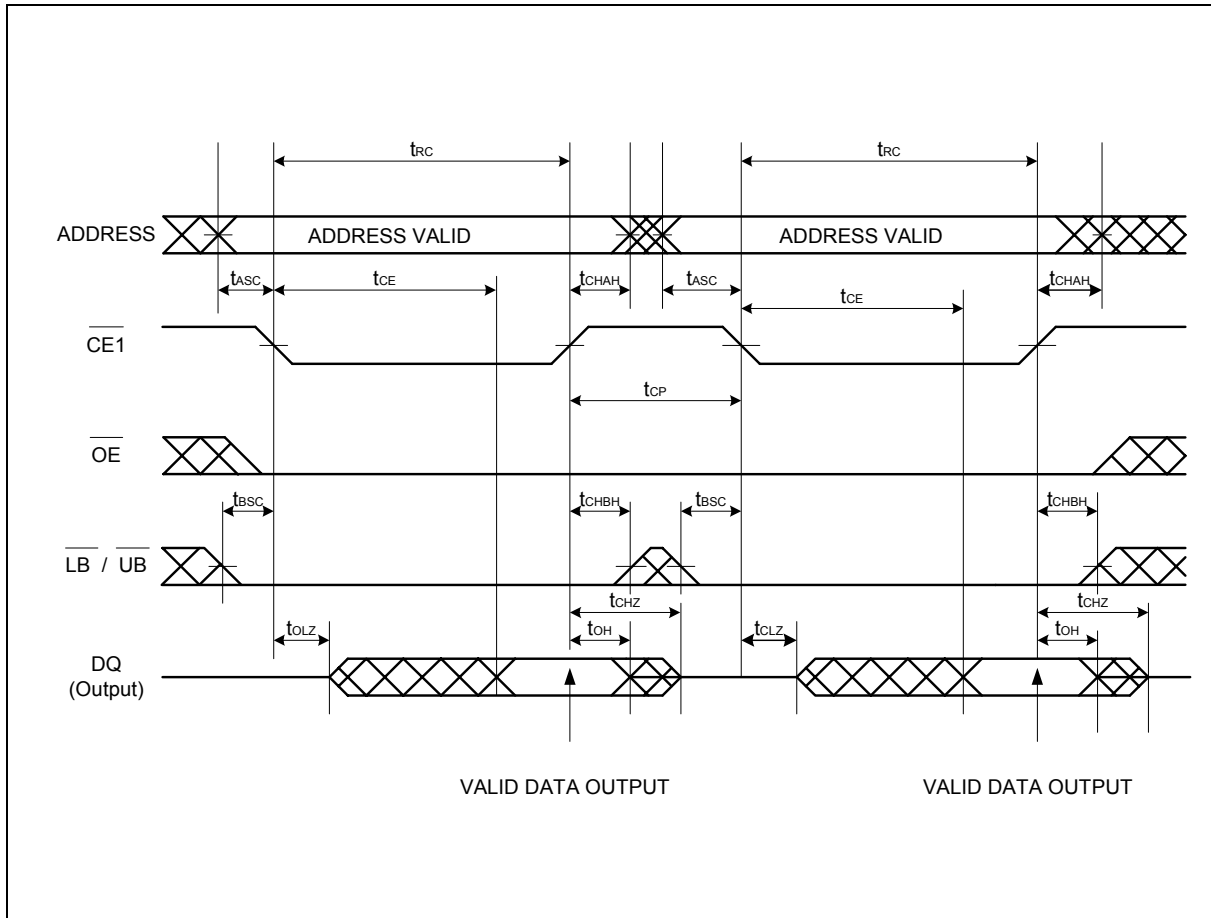
Note: $\overline{\text{CE2}}$, $\overline{\text{PE}}$ and $\overline{\text{WE}}$ must be High for entire read cycle.

Either or both $\overline{\text{LB}}$ and $\overline{\text{UB}}$ must be Low when both $\overline{\text{CE1}}$ and $\overline{\text{OE}}$ are Low.



Timing Waveforms, Continued

Read Timing #2 ($\overline{\text{CE1}}$ Control Access)



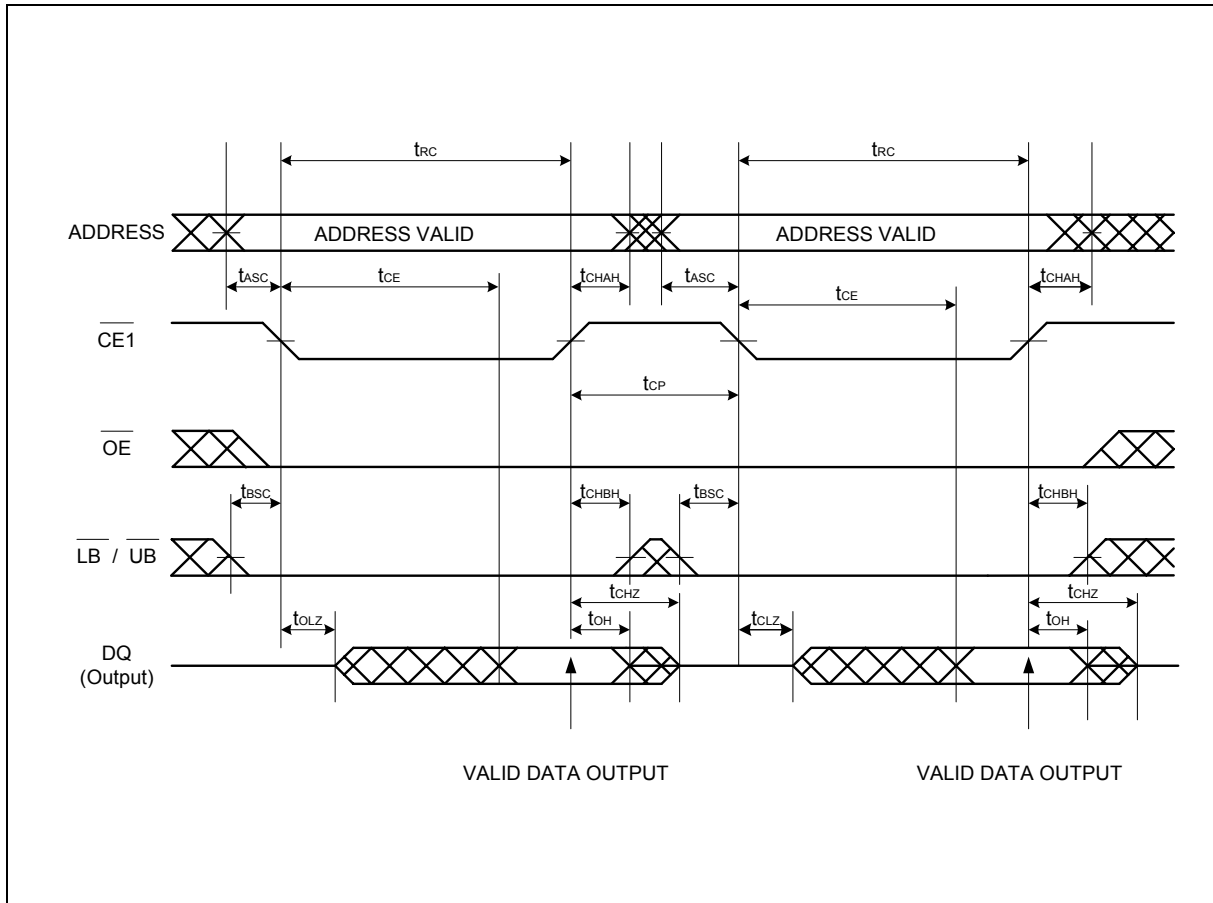
Note: $\overline{\text{CE2}}$, $\overline{\text{PE}}$ and $\overline{\text{WE}}$ must be High for entire read cycle.

Either or both $\overline{\text{LB}}$ and $\overline{\text{UB}}$ must be Low when both $\overline{\text{CE1}}$ and $\overline{\text{OE}}$ are Low.



Timing Waveforms, Continued

Read Timing #2 ($\overline{\text{CE1}}$ Control Access)



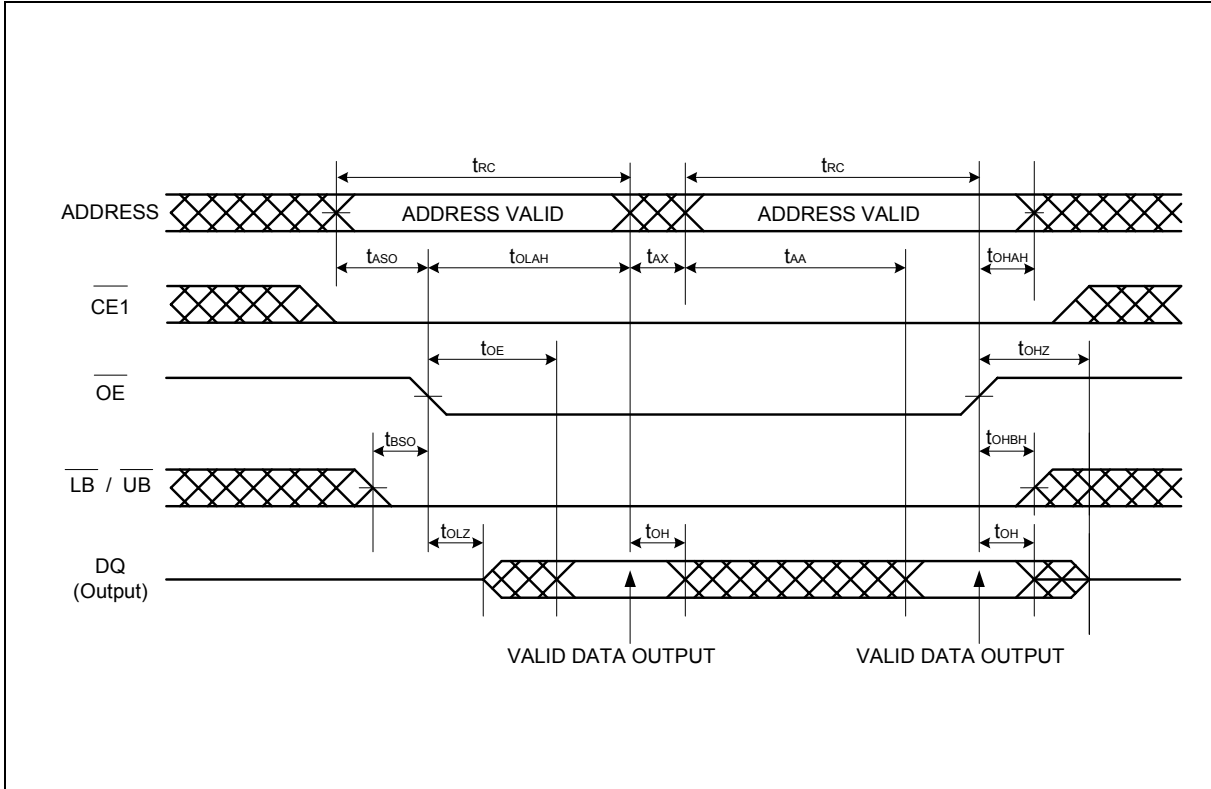
Note: $\overline{\text{CE2}}$, $\overline{\text{PE}}$ and $\overline{\text{WE}}$ must be High for entire read cycle.

Either or both $\overline{\text{LB}}$ and $\overline{\text{UB}}$ must be Low when both $\overline{\text{CE1}}$ and $\overline{\text{OE}}$ are Low.



Timing Waveforms, Continued

Read Timing #3 (Address Access after OE Control Access)



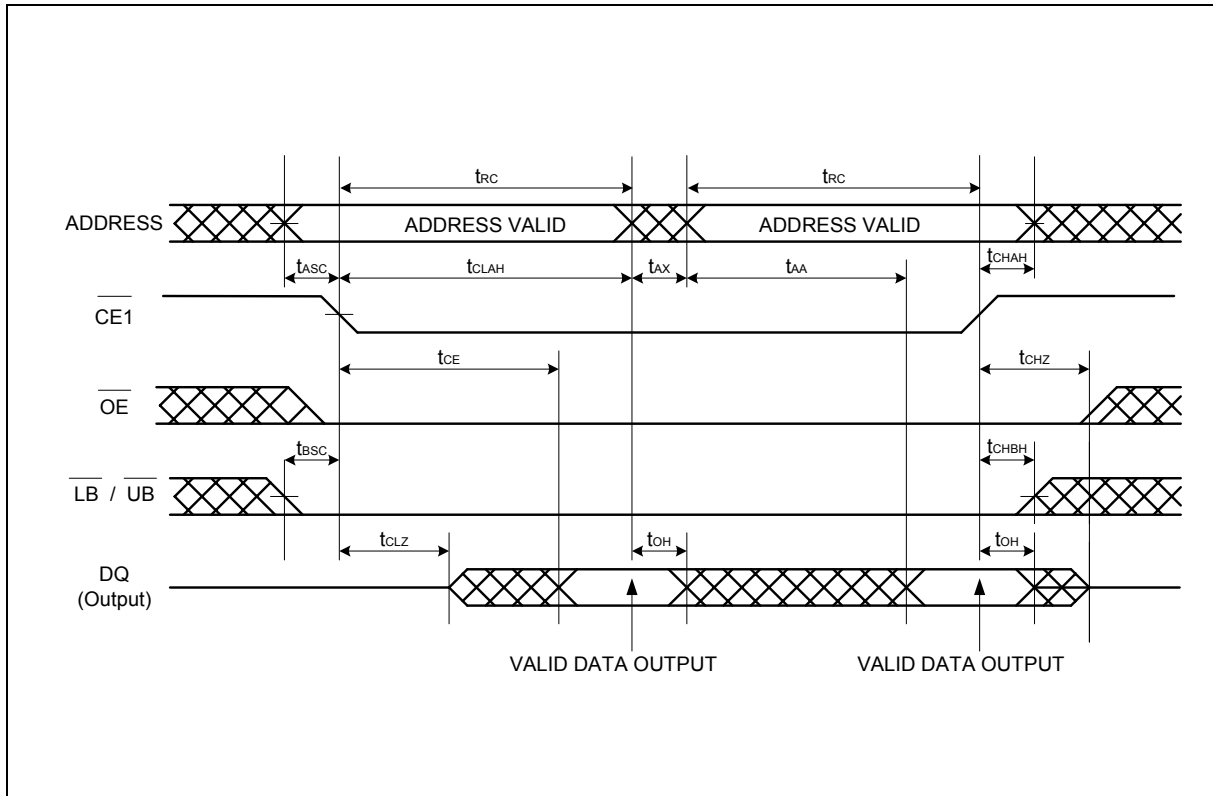
Note: CE2, PE and WE must be High for entire read cycle.

Either or both LB and UB must be Low when both CE1 and OE are Low.



Timing Waveforms, Continued

Read Timing #4 (Address Access after $\overline{\text{CE1}}$ Control Access)



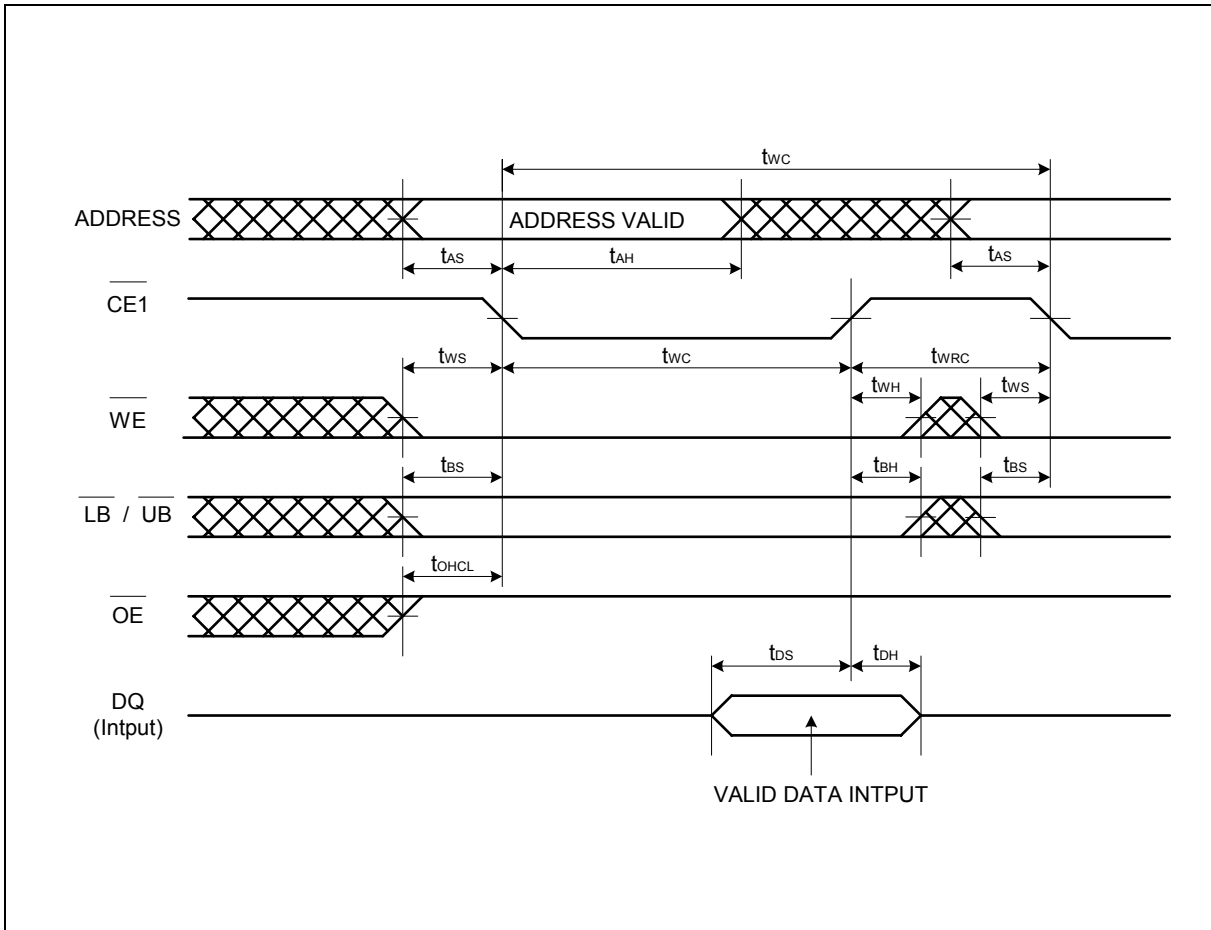
Note: $\overline{\text{CE2}}$, $\overline{\text{PE}}$ and $\overline{\text{WE}}$ must be High for entire read cycle.

Either or both $\overline{\text{LB}}$ and $\overline{\text{UB}}$ must be Low when both $\overline{\text{CE1}}$ and $\overline{\text{OE}}$ are Low.



Timing Waveforms, Continued

Write Timing #1 (CE1 Control)

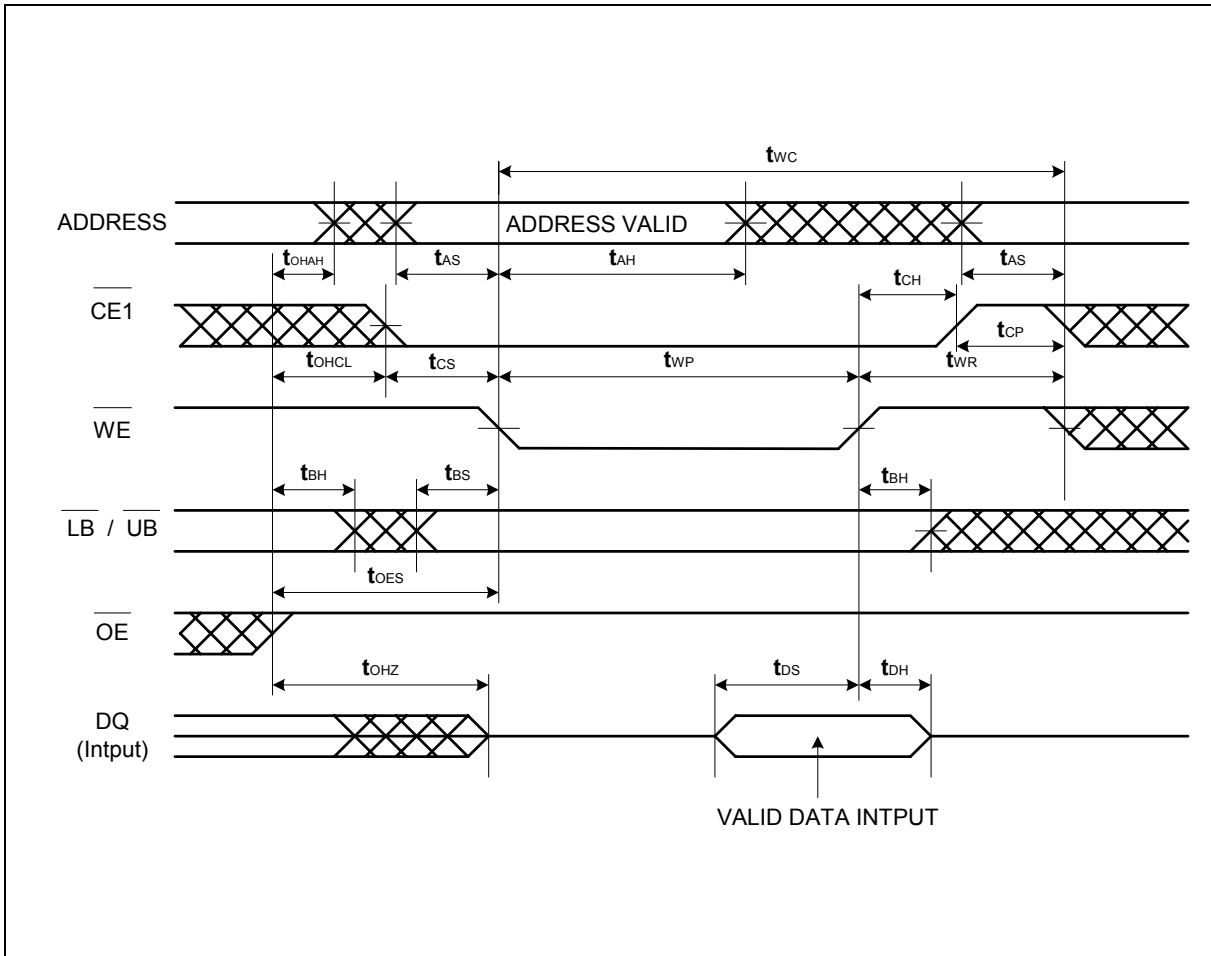


Note: CE2 and PE must be High for entire write cycle.



Timing Waveforms, Continued

Write Timing #2-1 ($\overline{\text{WE}}$ Control, Single Write Operation)

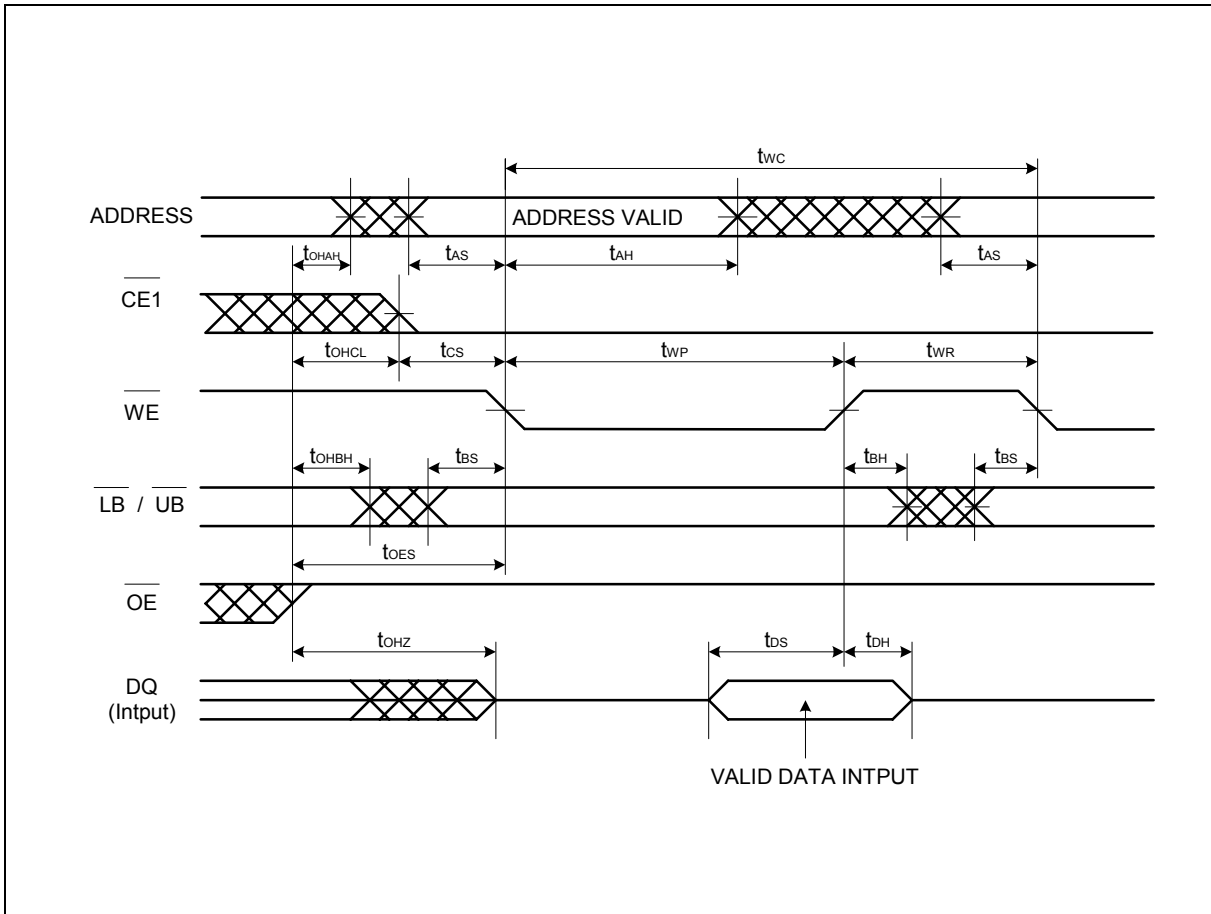


Note: $\overline{\text{CE2}}$ and $\overline{\text{PE}}$ must be High for entire write cycle.



Timing Waveforms, Continued

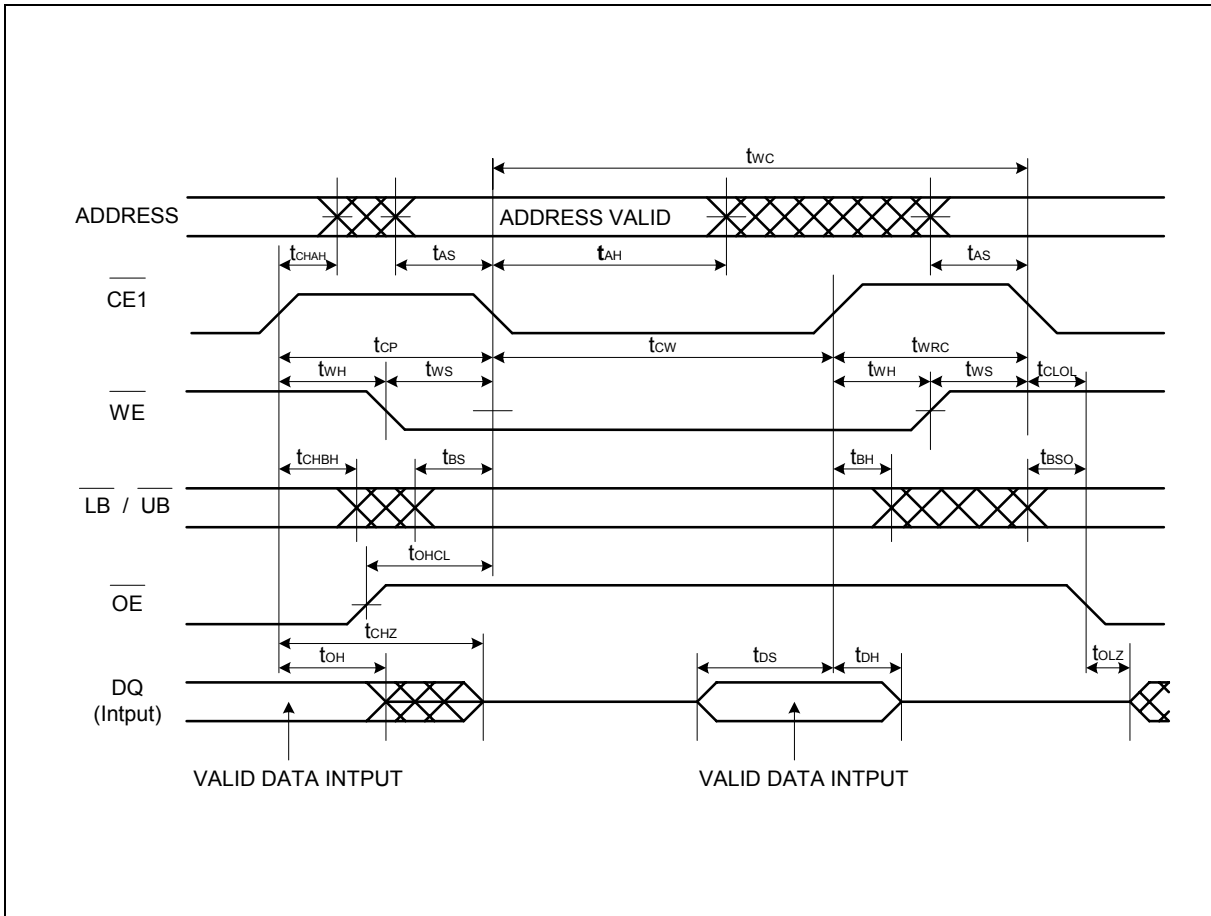
Write Timing #2 (WE Control, Continuous Write Operation)



Note: CE2 and PE must be High for entire write cycle.

Timing Waveforms, Continued

Read/Write Timing #1-1 (CE1 Control)

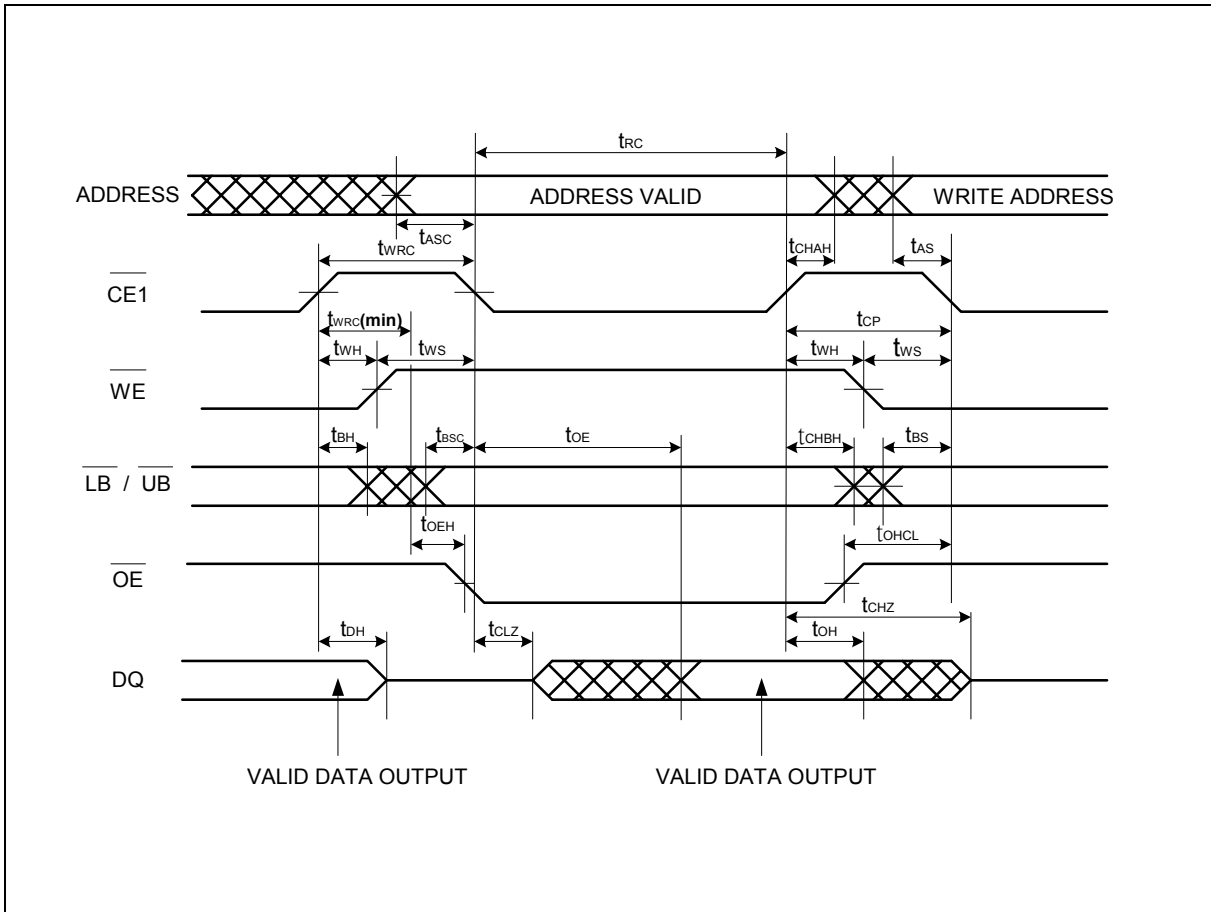


Note: Write address is valid from either $\overline{CE1}$ or \overline{WE} of last falling edge.



Timing Waveforms, Continued

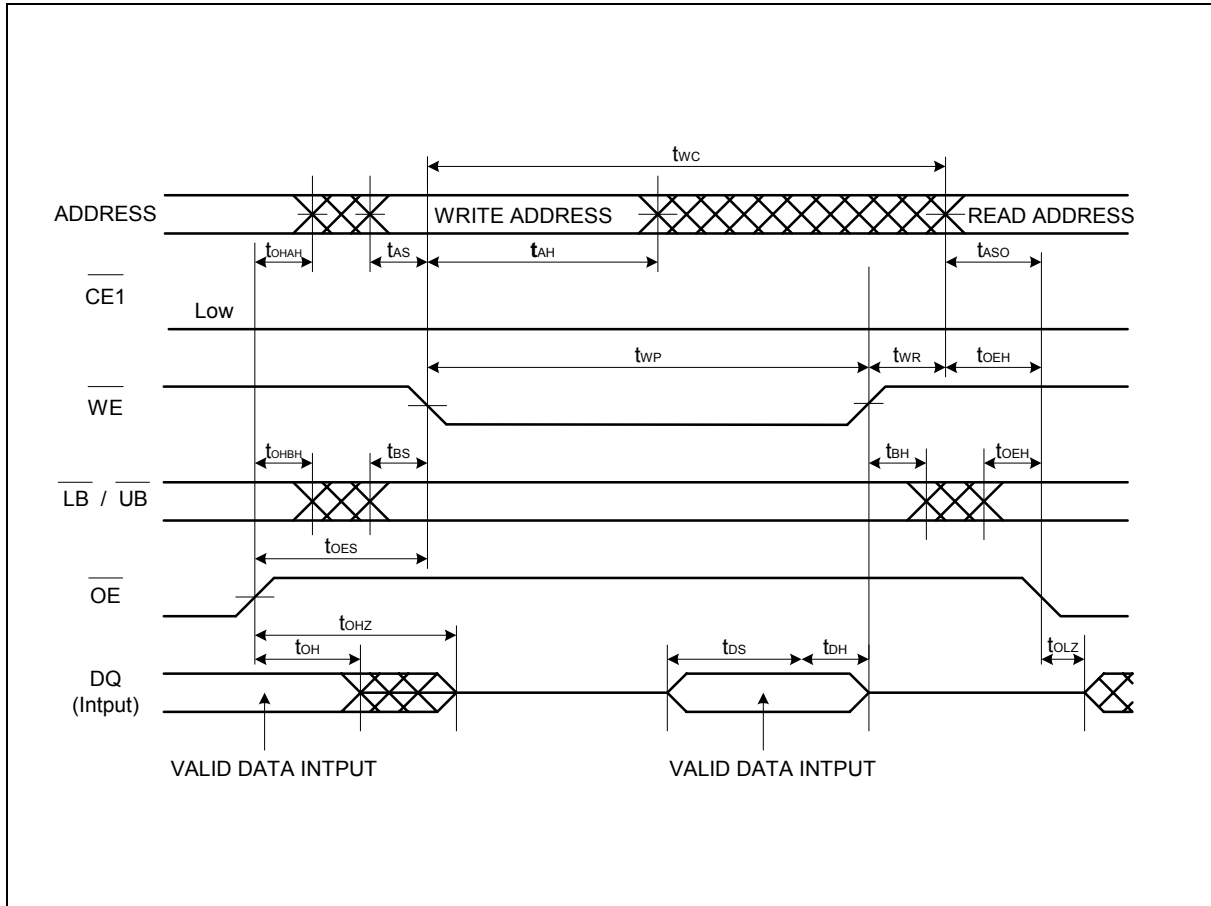
Read/Write Timing #1-2 (CE1 Control)



Note: The t_{OE} is specified from the time satisfied both t_{WRC} and $t_{WR(min)}$.

Timing Waveforms, Continued

Read ($\overline{\text{OE}}$ Control) / Write ($\overline{\text{WE}}$ Control) Timing #2-1



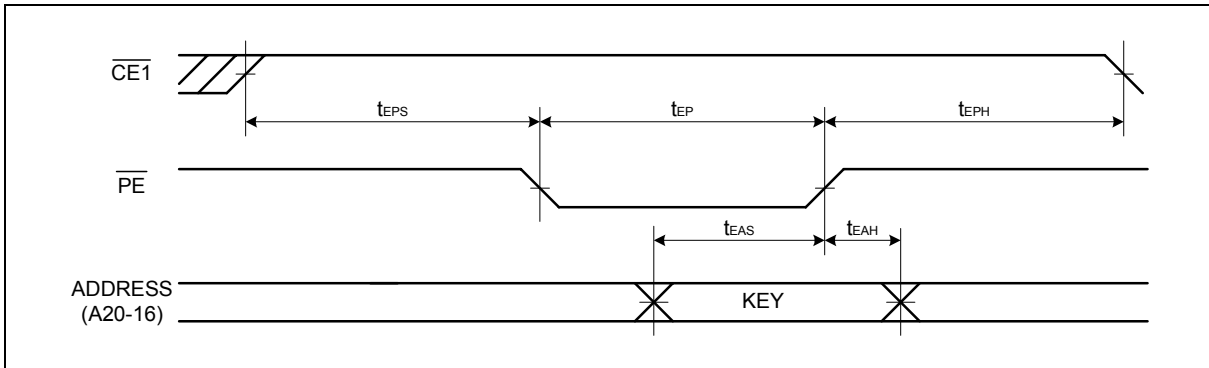
Note: $\overline{\text{CE1}}$ can be tied to Low for $\overline{\text{WE}}$ and $\overline{\text{OE}}$ controlled operation.

When $\overline{\text{CE1}}$ is tied to Low, output is exclusively controlled by $\overline{\text{OE}}$.



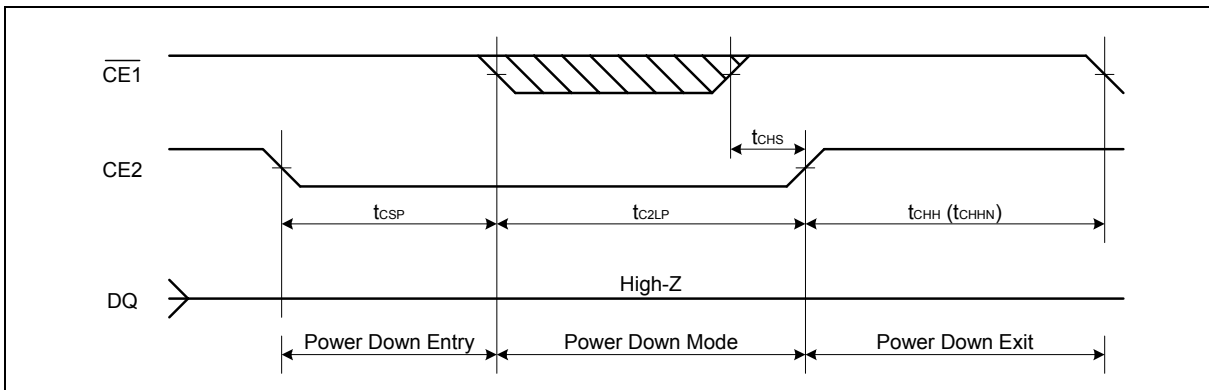
Timing Waveforms, Continued

Power Down Program Timing



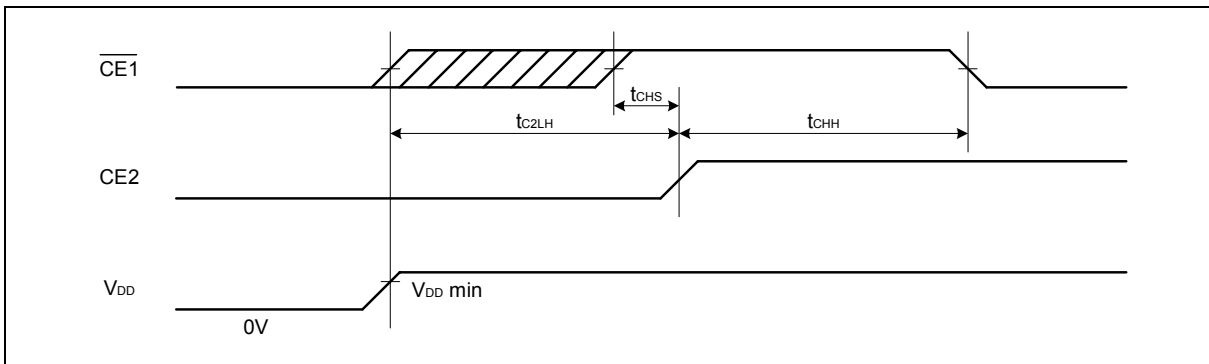
Note: CE2 must be High for Power Down Program operation.
Any other inputs not specified above can be either High or Low.

Power Down Entry and Exit Timing



Note: This Power Down mode can be also used for Power-up #2 below except that tCHHN can not be used at Power-up timing.

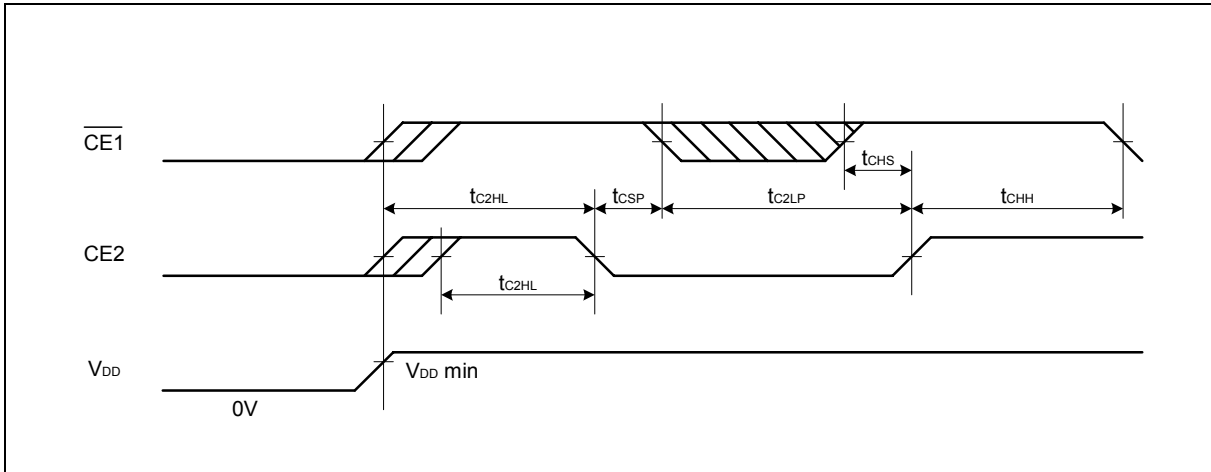
Power-up Timing #1



Note: The tC2LH specifies after VDD reaches specified minimum level.

Timing Waveforms, Continued

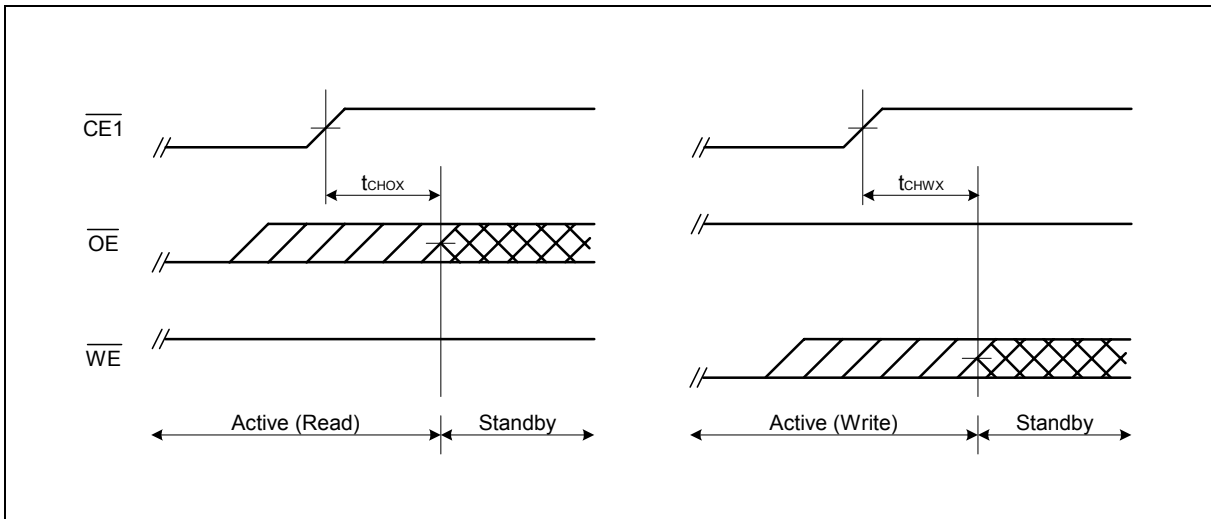
Power-up Timing #2



Note: The t_{C2HL} specifies from CE2 low to High transition after V_{DD} reaches specified minimum level.

$\overline{CE1}$ must be brought to High prior to or together with CE2 Low to High transition.

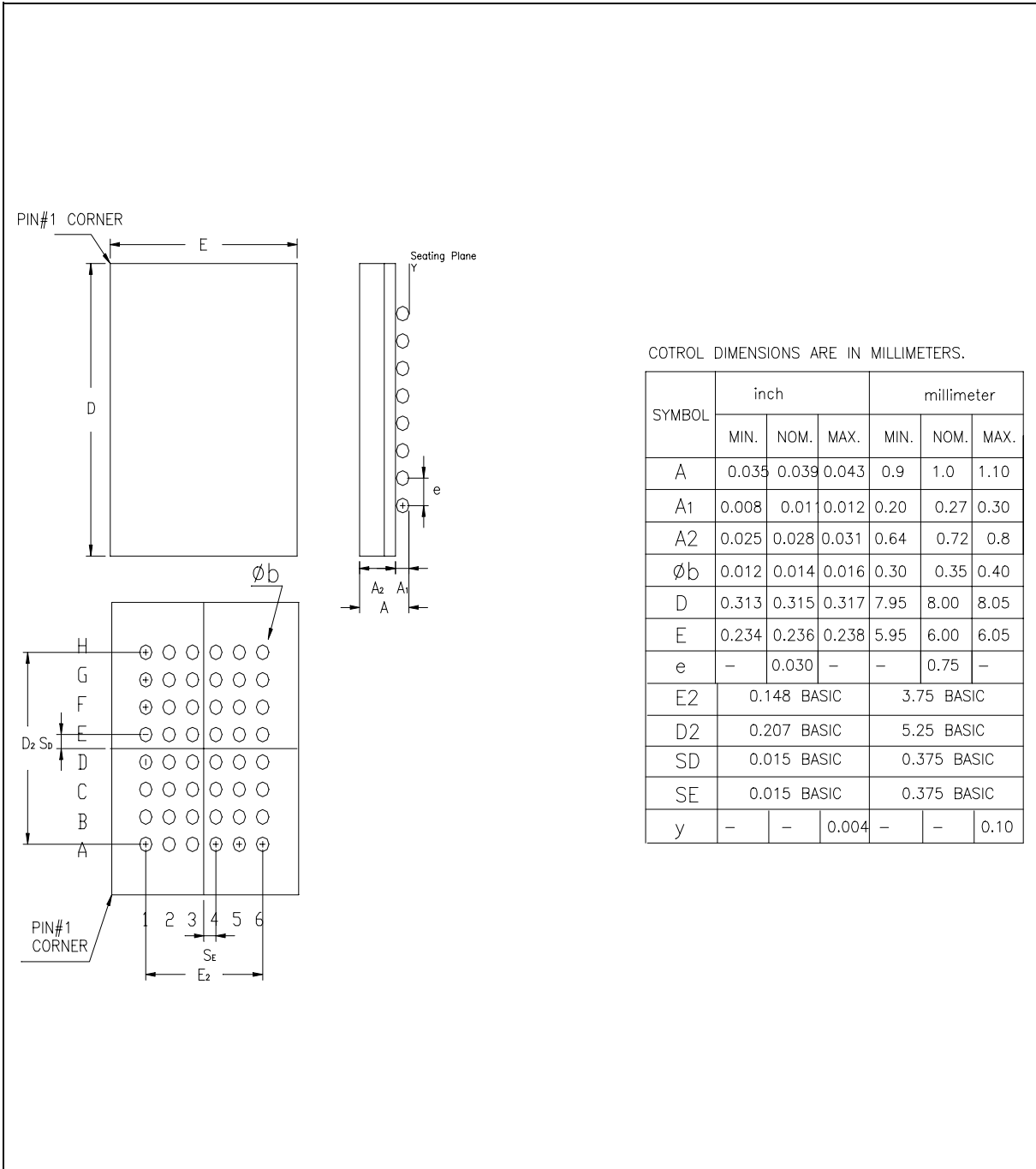
Standby Entry Timing after Read or Write



Note: Both t_{CHOX} and t_{CHWX} define the earliest entry timing for Standby mode. If either of timing is not satisfied, it takes $t_{RC(min)}$ period from either last address transition of A0, A1 and A2, or $\overline{CE1}$ Low to High transition.

10. PACKAGE DIMENSION

TFBGA 48 Balls (6 x 8 mm², pitch 0.75 mm)





11. ORDERING INFORMATION

| PART NO. | SPEED | OPERATING TEMPERATURE | PACKAGE |
|--------------|-------|-----------------------|---|
| W964B6BBN70 | 70 nS | 0 to 70 | TFBGA 48, 6 mm x 8 mm, BALL PITCH 0.75 mm |
| W964B6BBN70E | 70 nS | -25 to 85 | TFBGA 48, 6 mm x 8 mm, BALL PITCH 0.75 mm |
| W964B6BBN70I | 70 nS | -40 to 85 | TFBGA 48, 6 mm x 8 mm, BALL PITCH 0.75 mm |
| W964B6BBN80 | 80 nS | 0 to 70 | TFBGA 48, 6 mm x 8 mm, BALL PITCH 0.75 mm |
| W964B6BBN80E | 80 nS | -25 to 85 | TFBGA 48, 6 mm x 8 mm, BALL PITCH 0.75 mm |
| W964B6BBN80I | 80 nS | -40 to 85 | TFBGA 48, 6 mm x 8 mm, BALL PITCH 0.75 mm |

Notes:

1. Winbond reserves the right to make changes to its products without prior notice.
2. Purchasers are responsible for performing appropriate quality assurance testing on products intended for use in applications where personal injury might occur as a consequence of product failure.



12. VERSION HISTORY

| VERSION | DATE | PAGE | DESCRIPTION |
|---------|----------------|------|---------------------|
| A1 | March 31, 2003 | - | Create new document |



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